

Notice of References Cited	Application/Control No. 10/026,318	Applicant(s)/Patent Under Reexamination DEWA, ANDREW S.	
	Examiner Jack Dinh	Art Unit 2873	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,295,154	09-2001	Laor et al.	359/223
	B	US-5,606,447	02-1997	Asada et al.	359/199
	C	US-6,430,332	08-2002	Laor et al.	385/18
	D	US-2002/0018615	02-2002	Laor et al.	385/18
	E	US-2002/0034024	03-2002	Orcutt et al.	359/846
	F	US-2002/0034026	03-2002	Orcutt et al.	359/877
	G	US-2002/0070335	06-2002	Orcutt et al.	250/234
	H	US-2002/0074310	06-2002	Dewa, Andrew S.	216/22
	I	US-2002/0075553	06-2002	Orcutt, John W.	359/290
	J	US-2002/0118429	08-2002	Miyajima et al.	359/224
	K	US-2001/0022682	09-2001	McClelland et al.	359/280
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.